


<b>Search Notes</b>  	<b>Application/Control No.</b>  10531299	<b>Applicant(s)/Patent Under Reexamination</b>  KIM ET AL.
	<b>Examiner</b>  Jaisle, Cecilia M	<b>Art Unit</b>  1624

SEARCHED			
Class	Subclass	Date	Examiner
544	282	11/21/06	Cecilia Jaisle

SEARCH NOTES		
Search Notes	Date	Examiner
Searched in STN by STIC	07/12/2006	Cecilia Jaisle
Inventor Search done	7/19/06	Cecilia Jaisle

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
544	282	11/21/06	Cecilia Jaisle